

FORM PTO-1449	U.S. Department of Commerce Patent and Trademark Office	Att'y. Docket No. P25627	Application No. 10/749, 589
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (Use several sheets if necessary)		Applicant Takuya SEKIGUCHI et al	
		Filing Date January 2, 2004	Group 2673

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<div>OFFICE AUG 27 2004</div>		4	7	8	3	6	4	8	11/08/88	HOMMA et al	1	1	
		4	8	9	0	2	5	7	12/26/89	ANTHIAS et al	1	1	
		4	8	9	7	8	0	1	01/30/90	KAZAMA et al	1	1	
		4	9	5	4	8	1	8	09/04/90	NAKANE et al	1	1	
		5	0	9	1	7	1	7	02/25/92	CARRIE et al	1	1	
		5	7	2	0	0	1	6	02/17/98	EGASHIRA	1	1	
		5	7	3	4	3	8	0	03/31/98	ADAMS et al	1	1	
		5	8	2	5	3	5	9	10/20/98	DERBY et al	1	1	
	2004/	0	1	0	7	4	3	8	06/03/04	SEKIGUCHI et al.	1	1	
	2004/	0	1	1	9	7	0	6	06/24/04	SEKIGUCHI et al.	1	1	
2004/	0	1	3	0	5	4	0	07/08/04	SEKIGUCHI et al.	1	1		
2004/	0	0	8	0	5	4	0	04/29/04	SEKIGUCHI et al.	1	1		
2004/	0	1	3	0	5	6	3	07/08/04	SEKIGUCHI et al.	1	1		
2004/	0	1	3	0	5	7	7	07/08/04	SEKIGUCHI et al	1	1		
2004/	0	1	5	5	9	0	6	08/12/04	SEKIGUCHI et al.	1	1		

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
J.L.		0 7 4 7 8 0 5	11/12/96	E.P.O	—	—		
J.L.	9	8 / 1 3 7 5 2	04/02/98	W.I.P.O	—	—		
J.L.	2000	- 4 7 7 8 4	02/18/00	JAPAN	—	—		

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

J.L.	1	English Language Abstract of JP 2000-47784.
	2	An article entitled "Method for Keeping Windows from Overlapping Important Information," IBM Technical Disclosure Bulletin, IBM Corp., New York, Vol. 29, No. 10, pp. 4553-4554 (XP000011718, ISSN: 0018-8689).
	3	An article by COHEN, E. S. et al., entitled "Automatic Strategies in the Siemens RTL Tiled Window Manager," 2 <sup>nd</sup> IEEE Conference on Computer Workstations, U.S., Washington, IEEE Computer Society Press, pp. 111-119 (XP 00001098).
J.L.	4	European Search Report for European Patent Application No. EP 03075465.9, mailed on May 14, 2003.

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

~~APR 26 2006~~

**Application No.**  
**10/749,589**

**Filing Date**  
**January 2, 2004**

**Group  
2673**

[illegible][illegible][illegible]

DATE CONSIDERED

9/6/2008

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## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

[illegible]

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

[illegible]

EXAMINER ( *Jan Kegera* )

DATE CONSIDERED 9/6/06

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